Analytical Reference Materials International

Certificate of Analysis Certified Reference Material

Grade: **AISI 1045 / UNS G10450**Part Number (Q.A. NO.): **IARM 200**C

Certificate Date: 04/01/2010 Certificate No.: 200C-04012010-IARM-F Revision Date: 08/08/2014

Interpretation of Data

- 1. Certified values listed below reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community and are reported as % wt. unless otherwise noted.
- 2. Any data reported and enclosed by a parentheses () is a "best estimate" and is NOT CERTIFIED. This data could not be quantified sufficiently for certification. It was however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
- 3. The "Inter-laboratory Analysis Program" (ILAP) utilized in the establishment of the data are an ongoing program with permanent membership. Certain elements may be selected by a consensus of the members for more extensive testing. Therefore the data in **brackets** [] **indicates further testing is in process.**
- 4. The "±Estimated Uncertainty" is enclosed by a parentheses () below the individual element's concentration and is based on a Confidence Interval at 95%. Included in this estimated uncertainty, are the combined effects of method imprecision, material inhomogeneity, and any bias between methods.

Important: A "User Registration Card" accompanies all shipments. This card should be completed immediately upon receipt of materials with the appropriate user information. This is the only way in which ARMI can guarantee customer updates or possible data modifications!

Aluminum 0.002 (0.0005)	Antimony 0.002 (0.0004)	Arsenic 0.006 (0.0004)	<u>Bismuth</u>	Boron 0.0003 (0.0001)	Cadmium	Calcium 0.0020 (0.0002)	<u>Carbon</u> 0.453 (0.001)	Chromium 0.100 (0.001)	<u>Cobalt</u> 0.007 (0.0005)
Copper 0.236 (0.003)	<u>Lead</u>	Magnesium	Manganese 0.775 (0.003)	Molybdenum 0.023 (0.001)	Nickel 0.094 (0.001)	Niobium 0.0014 (0.0002)	Nitrogen 0.0079 (0.0001)	Oxygen 0.0037 (0.0003)	Phosphorus 0.007 (0.001)
<u>Selenium</u>	Silicon 0.241 (0.002)	<u>Sulfur</u> 0.020 (0.001)	<u>Tantalum</u>	<u>Tin</u> 0.0090 (0.0002)	Titanium 0.0011 (0.0002)	Tungsten (0.002)	Vanadium 0.025 (0.001)	<u>Zinc</u> (0.002)	Zirconium (0.004)

The laboratories participating in the "Inter-Laboratory Analysis Program" (ILAP) and certification of this material are as follows:

Anderson Laboratories, Inc. - Greendale, WI Colorado Metallurgical Services - Denver, CO Essar Steel Algoma, Inc. - Sault Ste. Marie, ON

Exova - Middlesbrough, UK

Laboratory Testing, Inc. - Hatfield, PA

Timken Steel Corp. - Canton, OH

ArcelorMittal Dofasco - Hamilton, ON Crucible Industries - Syracuse, NY

Exova - Gary, IN
Exova - Portland, OR

Severstal North America, Inc. - Mingo Junction, OH

TMK IPSCO - Koppel, PA

Traceability: All members of the "Inter-Laboratory Analysis Program" (ILAP) listed above validate test methods and instrument performance utilizing SRMs produced by the National Institute of Standards and Technology, (NIST) as well as other CRMs and RMs produced by recognized Certifying Bodies from around the world. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are: NIST 1163, IARM 28C, NIST 13G, 362, 1761, 1762, 1763, 1764, 1765, 1766, 1767, BAM 036-1, ALPHA AR668, AR1648, NIST 1761, 1762, 1763, 1764, 1765, 1766, 1767, NIST 20G, 361, 3102A, 3103A, 3106, 3107, 3109A, 3113, 3114, 3128, 3131A, 3136, 3149, 3165, 3168A, 3169, BS CSN2-2, LECO 501-644, 762-747, NIST 1161, 1163, 1167, BS 3952, 3961, BCS 252/1, 410, 453/1, SS 456/1, ES 096-1, LECO 501-644, BS 3941, NIST 16F, 33B, 33E, 293, 368, 391, 1160, 1161, 1162, 1163, 1164, 1217, 1754, 1760, 1761, 1762, 1763, 1764, 1765, 1766, 1767, BAS 401/1, 402/1, 403/1, 404/1, 405/1, 407/2, 408/1, 409/1, 410/2, JSS ST01, ST02, ST03, ST04, ST05, ST06, 168-4, 169-4, 170-4, 171-4, 172-4, 173-4, 174-4, 175-4, BS CA-1, CA-2, CA-3, CA-4, CA1A, CA3A, XAAS, XCCV, XCCS, LECO 501-510, 501-504, SNIST 361, 362, 363, 364, IARM 200B, LECO 501-504, 501-551, 501-644, SUS C17, D8, RE 12/19, INOX, BS CSN2-1, CSN3, CSN4, NIST 1264A, 1764, IARM 28H, 254A, 270A, LECO 501-644CKD 169, 170, BS CA-3, 14A, 50B, 64B, 70B, ALPHA AR662, NIST 361, 1763A, 1764, IARM 200A, RE12/2, RN13/10, RN14/18, RN5/28, RN2/19, RH12/3, RH18/10, RH31/8, NZ 6000, BS 56E, LECO 762-747.

A specific line of traceability is established to NIST and other Certifying Bodies for those elements that are noted as "Certified Values" on the Certificates of Analyses referenced above.

See Reverse Side for Statistical Data and Additional Information Regarding this Material.

The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material as of 08/08/2014.

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200C	Al	As	В	С	Co	Cr	Cu	Mn	Мо	N	Nb	Ni	0	P	Pb
1	0.0024	0.0061	0.0004	0.4549	0.0070	0.0999	0.2420	0.7722	0.0250	0.00763	0.0011	0.090	0.00337	0.0080	0.0004
2	0.0035	0.0061	0.0002	0.4544	0.0064	0.1009	0.2415	0.7814	0.0239	0.0080	0.00093	0.096	0.0041	0.008	0.0007
3	0.0018	0.007	0.00031	0.4523	0.0065	0.1000	0.2363	0.7793	0.0215	0.00807	0.0013	0.09693	0.0037	0.00526	0.0048
4	0.0029	0.0056	0.00027	0.453	0.0065	0.0969	0.2297	0.7772	0.0240	0.0077	0.0016	0.09567	0.004	0.00667	0.0050
5	0.0019	0.0065	0.00034	0.4529	0.0071	0.0987	0.2410	0.7709	0.0205	0.0077	0.0014	0.0908	0.00340	0.0058	0.0074
6	0.0023	0.0067	0.0004	0.453	0.0077	0.0999	0.2421	0.7713	0.0232	0.0080	0.0017	0.0940	0.00382	0.0078	0.0007
7	0.0024	0.0055	0.0005	0.454	0.0075	0.099	0.236	0.779	0.023	0.0082	0.0015	0.0938	0.0036	0.0057	
8	0.0019	0.0057	0.0002	0.4531		0.103	0.238	0.771	0.024	0.00776		0.097		0.0060	
9	0.00325	0.0074				0.099	0.233	0.7772	0.024	0.0078		0.093		0.0057	
10		0.0061				0.0983	0.2342	0.773	0.0212	0.00828		0.095		0.0067	
11						0.095	0.233	0.7715	0.023	0.0078		0.0934		0.0054	
12						0.1041	0.2288		0.0239			0.090		0.0060	
13						0.1008			0.0239			0.0959		0.0077	
14												0.09385			
Mean	0.0025	0.0063	0.0003	0.4534	0.0070	0.0997	0.2363	0.7749	0.0232	0.0079	0.0014	0.0940	0.0037	0.0065	0.0032
STDV.	0.0006	0.0006	0.0001	0.0009	0.0005	0.0024	0.0047	0.0040	0.0013	0.0002	0.0003	0.0024	0.0003	0.0010	0.0030
Certified	0.002	0.006	0.0003	0.453	0.007	0.100	0.236	0.775	0.023	0.0079	0.0014	0.094	0.0037	0.007	
95% C.I.	0.0005	0.0004	0.0001	0.001	0.0005	0.001	0.003	0.003	0.001	0.0001	0.0002	0.001	0.0003	0.001	
Methods	I,O	X,I,O	0	C,O	X,I,O	X,I,O	X,I,O	X,I,O	X,I,O	F,O	X,I,O	X,I,O	F,O	X,I,O	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

200C	S	Si	Sn	Ti	V	W	Bi	Ca	Н	Mg	Sb	Se	Та	Zn	Zr
1	0.0186	0.240	0.00893	0.00085	0.0240	0.00246	0.000001	0.00179	0.0002	0.00025	0.0022	0.000004	0.0007	0.0023	0.0060
2	0.0197	0.242	0.00943	0.0008	0.0257	0.0025	0.0005	0.0024	0.000024	0.0002	0.0018	0.0011	<0.001	0.0018	0.00059
3	0.0190	0.23938	0.0095	0.0016	0.0255	0.0020	< 0.001	0.0023	0.0002	0.0001	0.0015	0.0012	< 0.004	0.0019	0.0053
4	0.0181	0.24083	0.0091	0.0013	0.0245	0.0025	0.0034	0.0021			0.0021	<0.003	0.0029	0.0017	0.0011
5	0.0211	0.2438	0.0084	0.0010	0.0233	0.0021		0.00184			0.0017	0.0005			0.0008
6	0.0207	0.2359	0.0089	0.0008	0.0250			0.0020			0.0010				0.0075
7	0.0200	0.2434	0.0090	0.0011	0.0252			0.0020			0.0011				0.0031
8	0.0209	0.236	0.0088	0.0014	0.02485			0.0015							
9	0.0194	0.242	0.0091	0.0009	0.0242										
10	0.0210	0.242	0.0085		0.0251										
11	0.0198	0.2402	0.0093												
12		0.239													
13		0.2432													
Mean	0.0198	0.2406	0.0090	0.0011	0.0247	0.0023	0.0013	0.0020	0.0001	0.0002	0.0016	0.0007	0.0018	0.0019	0.0035
STDV.	0.0010	0.0026	0.0003	0.0003	0.0007	0.0002	0.0018	0.0003	0.0001	0.0001	0.0005	0.0006	0.0016	0.0002	0.0028
Certified	0.020	0.241	0.0090	0.0011	0.025	(0.002)		0.0020			0.002			(0.002)	(0.004)
95% C.I.	0.001	0.002	0.0002	0.0002	0.001			0.0002			0.0004				
Methods	C,O	X,I,O	X,I,O	X,I,O	X,I,O	X,I,O		I,O			X,I,O			X,I,O	I,O

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30-1992 list the following:

<u>Certifying Body:</u> Any technically competent body (organization or firm, public or private) that issues a reference material certificate, which provides the information, detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards - Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology, (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance one or more of whose property values are sufficiently homogeneous and well established to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

<u>Certified Reference Material (CRM):</u> Reference material, accompanied by a certificate, one or more of whose property values are certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

Inter-Laboratory Analysis Program (ILAP): Although ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", it is also a well thought out and logical plan for conducting an inter-laboratory program involving multiple techniques. Therefore, the planning, conducting, analyzing, protocol, and treatment of data resulting from this inter-laboratory program were performed utilizing the guidelines established in ASTM E691-87.

<u>Methods of Analysis:</u> In view of the fact, that the "Inter-Laboratory Analysis Program" entails a wide variety of materials, no single analytical method would provide optimum data results. Therefore, the methods utilized were a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, and X-Ray spectrometric methods. The determinations for Carbon, Sulfur, Nitrogen, and Oxygen are the result of combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing as these processes may contaminate the surface. When not in use, the material should be stored in a cool, dry location. This material was tested using both the solid disks and chips prepared from the disks. The certified values are considered representative of the overall average composition of the material. Chips are not intended to be used for Oxygen analysis.

Selection of Materials: A "batch" or "series" is defined as a single bar of one continuous length and heat. The majority of materials are in wrought condition; other methods of manufacture are utilized as a less desirable resort. ILAP samples are taken by removing a section, a minimum of, every one-twelfth of total length from the entire bar. A portion of the section is converted to chips and thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis. This systematic sampling procedure results in the homogeneity being reflected as a product of the overall statistics and certified data. This method of homogeneity testing is in accordance with ISO Guide 34, regarding the systematic selection and testing of a representative number of units for the assessment of homogeneity.

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Certificate No.: 200C-04012010-IARM-F
Certificate Date: 04/01/2010

Revision Date/No.: 08/08/2014